

August 2014

FCP20N60 / FCPF20N60 N-Channel SuperFET MOSFET 600 V, 20 A, 190 m Ω

Features

- 650V @ T_J = 150°C
- Typ. $R_{DS(on)}$ = 150 m Ω
- Ultra Low Gate Charge (Typ. Q_q = 75 nC)
- Low Effective Output Capacitance (Typ. $C_{oss(eff.)} = 165 pF$)
- · 100% Avalanche Tested

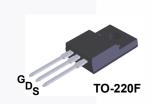
Applications

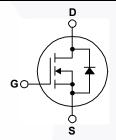
- · Solar Inverter
- AC-DC Power Supply

Description

SuperFET® MOSFET is Fairchild Semiconductor's first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low onresistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.







Absolute Maximum Ratings

Symbol		Parameter		FCP20N60	FCPF20N60	Unit
V _{DSS}	Drain-Source Volta	age		6	00	V
I _D	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		20 12.5	20* 12.5*	A A
I _{DM}	Drain Current	- Pulsed	(Note 1)	60	60*	Α
V _{GSS}	Gate-Source Volta	ige		±	30	V
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	6	90	mJ
I _{AR}	Avalanche Curren	t	(Note 1)	2	20	Α
E _{AR}	Repetitive Avalance	che Energy	(Note 1)	2	0.8	mJ
dv/dt	Peak Diode Recov	/ery dv/dt	(Note 3)	4	1.5	V/ns
P_D	Power Dissipation	(T _C = 25°C) - Derate Above 25°C		208 1.67	39 0.3	W/°C
T _{J,} T _{STG}	Operating and Sto	rage Temperature Range		-55 to	+150	°C
T _L	Maximum Lead Te 1/8" from Case for	emperature for Soldering, 5 Seconds		3	00	°C

^{*}Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FCP20N60	FCPF20N60	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.6	3.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

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Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCP20N60	FCP20N60	TO-220	Tube	N/A	N/A	50 units
FCPF20N60	FCPF20N60	TO-220F	Tube	N/A	N/A	50 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
D\/	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	600	-	-	V
BV _{DSS}	Drain to Source Breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 150^{\circ} C$	-	650	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
BV _{DS}	Drain-Source Avalanche Breakdown Voltage	V _{GS} = 0 V, I _D = 20 A	_	700	-	V
	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V	-	-	1	^
I _{DSS}	Zero Gate voltage Drain Current	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	10	μΑ
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	0.15	0.19	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 10 A	-	17	-	S

Dynamic Characteristics

_						
C _{iss}	Input Capacitance	V 05.V.V 0.V	-	2370	3080	pF
C _{oss}	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	-	1280	1665	pF
C _{rss}	Reverse Transfer Capacitance	1 = 1 1/11/12	-	95	-	pF
C _{oss}	Output Capacitance	V _{DS} = 480 V, V _{GS} = 0 V, f = 1 MHz	-	65	85	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V	-	165	-	pF
Qg	Total Gate Charge at 10V	V _{DS} = 480 V, I _D = 20 A,	-	75	98	nC
Q _{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	13.5	18	nC
Q _{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	36	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		/-	62	135	ns
t _r	Turn-On Rise Time	V _{DD} = 300 V, I _D = 20 A,	-	140	290	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_G = 25 Ω	-	230	470	ns
t _f	Turn-Off Fall Time	(Note 4)	-	65	140	ns

Drain-Source Diode Characteristics

IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	20	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	60	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 20 A	-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 20 A,	-	530	11 - 15	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	_	10.5	-	μС

Notes:

- 1: Repetitive rating: pulse-width limited by maximum junction temperature.
- 2: I_{AS} = 10 A, V_{DD} = 50 V, R_{G} = 25 Ω , starting T_{J} = 25°C.
- 3: I $_{SD}~\leq 20$ A, di/dt ≤ 200 A/µs, V $_{DD} \leq BV _{DSS},$ starting T $_{J}$ = 25°C.
- 4: Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

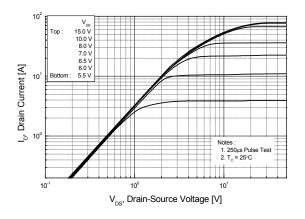


Figure 2. Transfer Characteristics

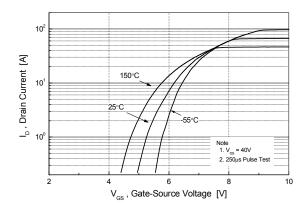


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

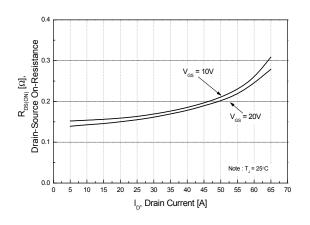


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

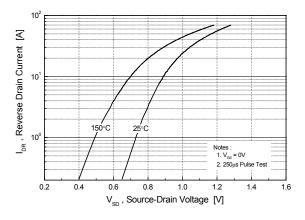


Figure 5. Capacitance Characteristics

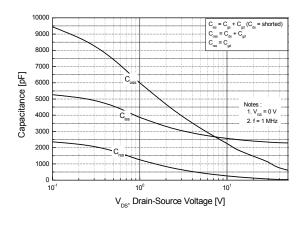
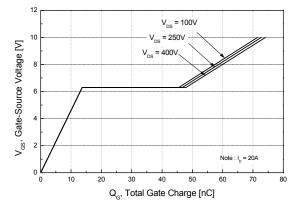


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

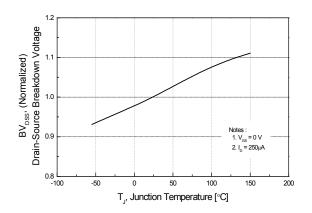


Figure 8. On-Resistance Variation vs. Temperature

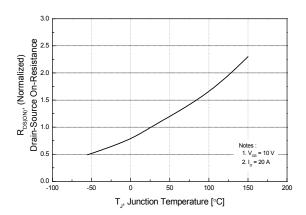


Figure 9-1. Maximum Safe Operating Area for FCP20N60

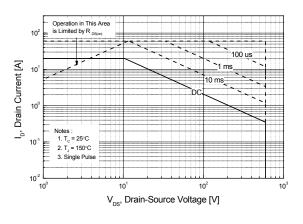


Figure 9-2. Maximum Safe Operating Area for FCPF20N60

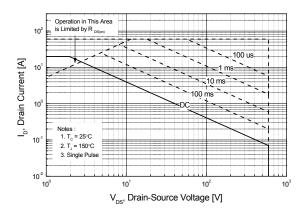
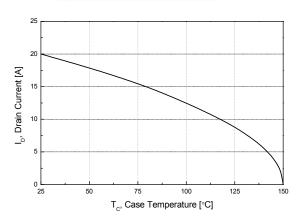


Figure 10. Maximum Drain Current vs. Case Temperature



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Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FCP20N60

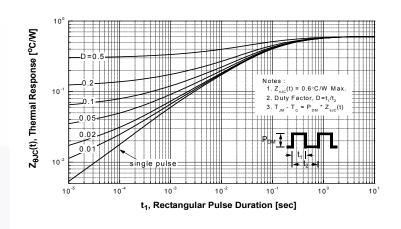
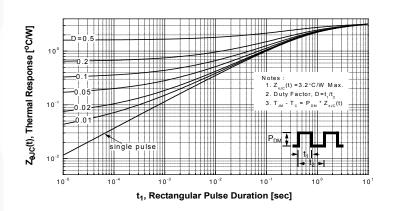


Figure 11-2. Transient Thermal Response Curve for FCPF20N60



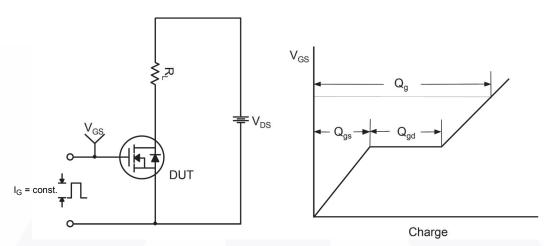


Figure 12. Gate Charge Test Circuit & Waveform

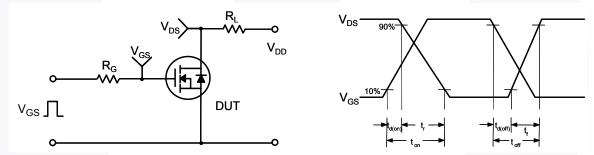


Figure 13. Resistive Switching Test Circuit & Waveforms

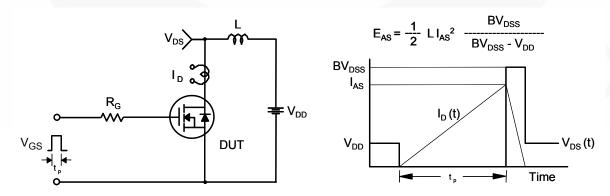


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

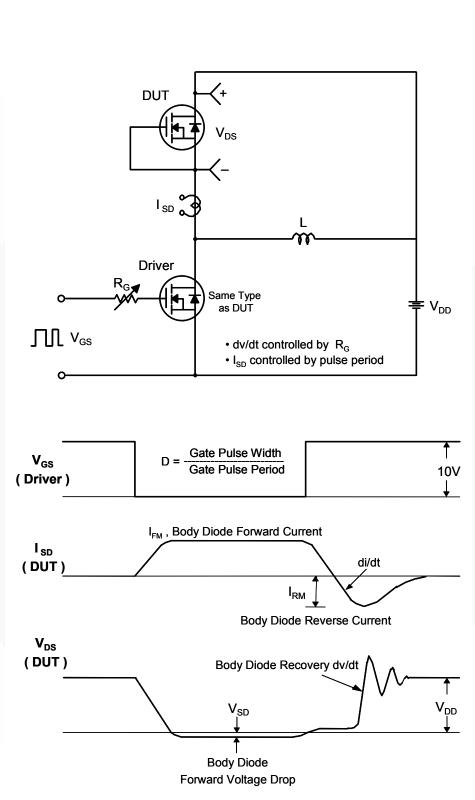
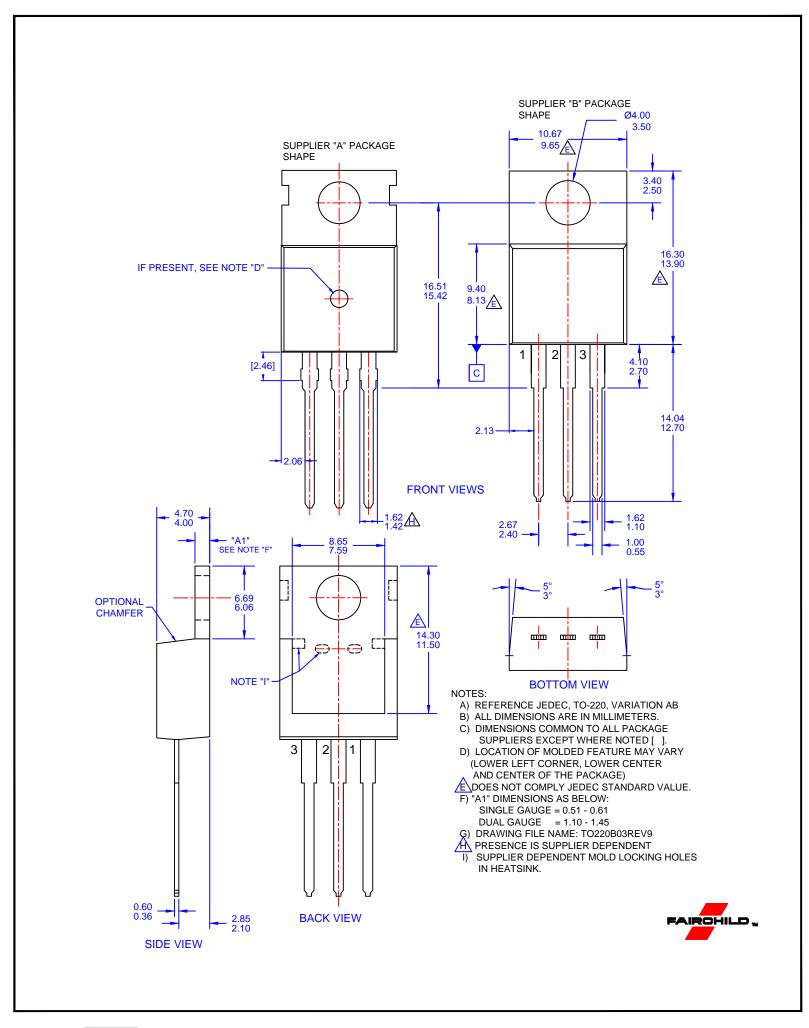
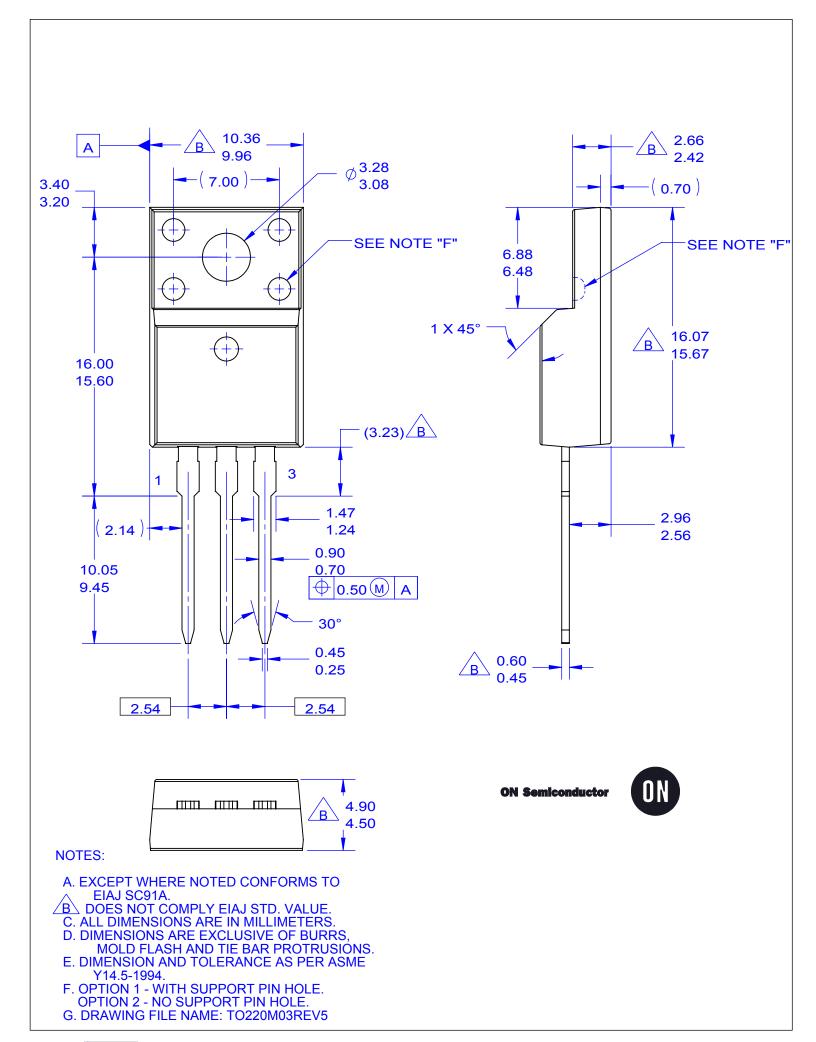


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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